Searcn Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/650,461	DAWES, DAVID
Examiner	Art Unit

Derek L. Dupuis

2883

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH) .
	DATE	EXMR
Updated BRS search in EAST (USPAT, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB) - see attached search history printout	3/20/2006	DLD
Search in NPL: Optics Letters database	3/19/2006	DLD
<i>:</i>		
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